



FQD12P10 / FQU12P10

100V P-Channel MOSFET

General Description

These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as audio amplifier, high efficiency switching DC/DC converters, and DC motor control.

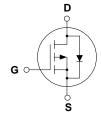
Features

- -9.4A, -100V, $R_{DS(on)}$ = 0.29 Ω @V_{GS} = -10 V Low gate charge (typical 21 nC)
- Low Crss (typical 65 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- · RoHS Compliant









Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQD12P10 / FQU12P10	Units
V _{DSS}	Drain-Source Voltage		-100	V
I _D	Drain Current - Continuous (T _C = 25°C) - Continuous (T _C = 100°C)		-9.4	Α
			-6.0	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	-37.6	Α
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy (N		370	mJ
I _{AR}	Avalanche Current	(Note 1)	-9.4	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	5.0	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-6.0	V/ns
P_{D}	Power Dissipation (T _A = 25°C) *		2.5	W
	Power Dissipation (T _C = 25°C)		50	W
	- Derate above 25°C	•	0.4	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		2.5	°C/W
$R_{\theta JA}$	R _{0JA} Thermal Resistance, Junction-to-Ambient *		50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		110	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	racteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	-100			V
ΔBV_{DSS} / ΔT_{J}	Breakdown Voltage Temperature Coefficient	$I_D = -250 \mu\text{A}$, Referenced to 25°C	;	-0.1		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -100 V, V _{GS} = 0 V			-1	μΑ
		V _{DS} = -80 V, T _C = 125°C		-	-10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse V _{GS} = 30 V, V _{DS} = 0 V				100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-2.0		-4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = -10 \text{ V}, I_D = -4.7 \text{ A}$		0.24	0.29	Ω
9 _{FS}	Forward Transconductance	V _{DS} = -40 V, I _D = -4.7 A (Note 4)		6.3		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V _{DS} = -25 V, V _{GS} = 0 V, f = 1.0 MHz		620 220 65	800 290 85	pF pF
	ng Characteristics					P.
t _{d(on)}	Turn On Dolay Timo			15	40	ns
t _r	Turn-On Rise Time	$V_{DD} = -50 \text{ V}, I_{D} = -11.5 \text{ A},$ $R_{G} = 25 \Omega$		160	330	ns
t _{d(off)}	Turn-Off Delay Time	11.6 - 20 32		35	80	ns
t _f	Turn-Off Fall Time	(Note 4, 5)	60	130	ns
Qg	Total Gate Charge	V _{DS} = -80 V, I _D = -11.5 A,		21	27	nC
Q _{gs}	Gate-Source Charge	V _{GS} = -10 V		4.6		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)	11.5		nC
Drain-S	ource Diode Characteristics a	nd Maximum Ratings				
I _S	Maximum Continuous Drain-Source Diode Forward Current				-9.4	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F				-37.6	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -9.4 \text{ A}$			-4.0	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = -11.5 \text{ A},$		110		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		0.47		μC

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 6.3mH, I_{AS} = -9.4A, V_{DD} = -25V, R_{G} = 25 Ω , Starting T_{J} = 25°C 3. I_{SD} \leq -11.5A, di/dt \leq 300A/ μ s, V_{DD} \leq BV $_{DSS}$, Starting T_{J} = 25°C 4. Pulse Test : Pulse width \leq 300 μ s, Duty cycle \leq 2% 5. Essentially independent of operating temperature

Typical Characteristics

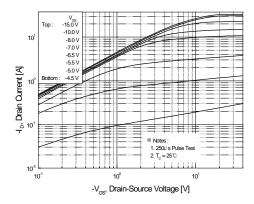


Figure 1. On-Region Characteristics

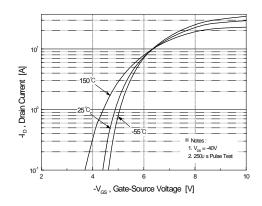


Figure 2. Transfer Characteristics

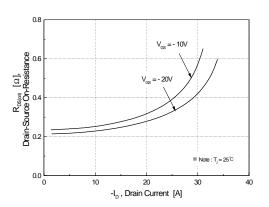


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

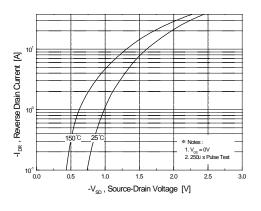


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

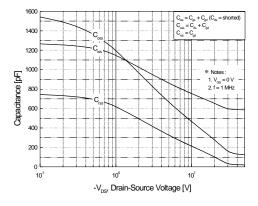


Figure 5. Capacitance Characteristics

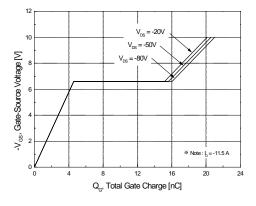


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)

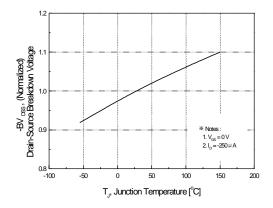
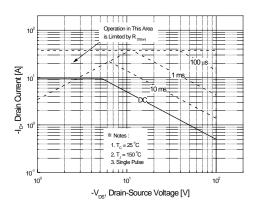


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



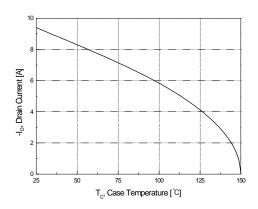


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

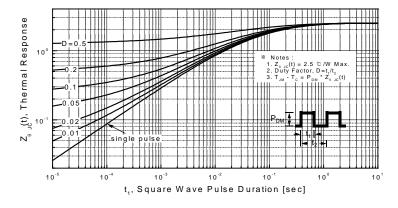
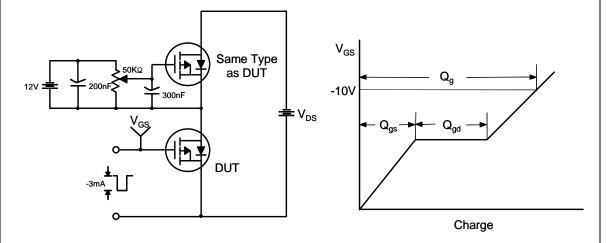


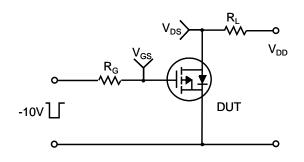
Figure 11. Transient Thermal Response Curve

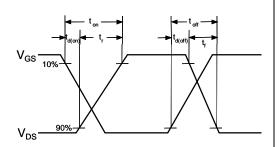
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Gate Charge Test Circuit & Waveform

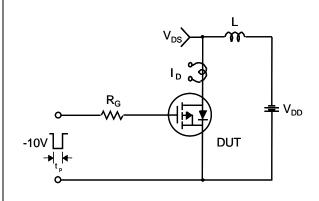


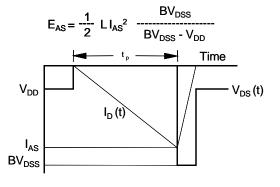
Resistive Switching Test Circuit & Waveforms



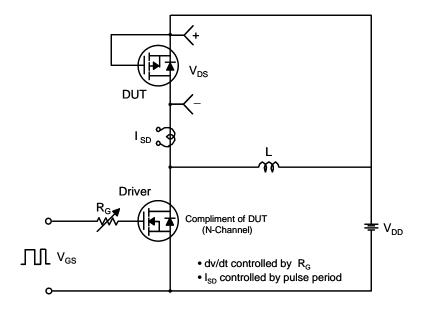


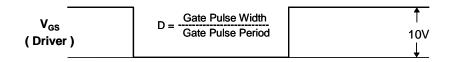
Unclamped Inductive Switching Test Circuit & Waveforms

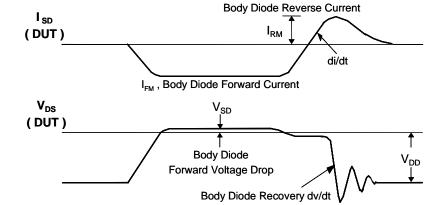




Peak Diode Recovery dv/dt Test Circuit & Waveforms



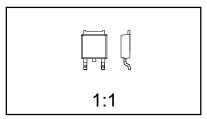




Package Dimensions

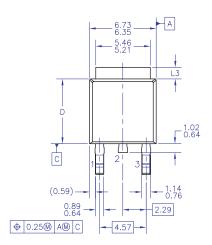
TO-252 (DPAK) (FS PKG Code 36)

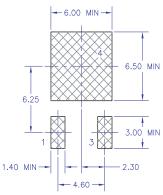




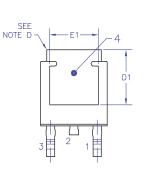
Scale 1:1 on letter size paper Dimensions shown below are in: millimeters

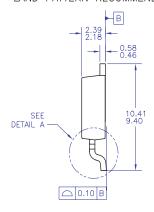
Part Weight per unit (gram): 0.33

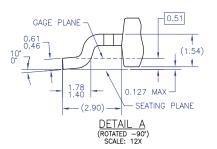




LAND PATTERN RECOMMENDATION







- NOTES: UNLESS OTHERWISE SPECIFIED

 A) ALL DIMENSIONS ARE IN MILLIMETERS.

 B) THIS PACKAGE CONFORMS TO JEDEC, TO-252, ISSUE C, VARIATION AA & AB, DATED NOV. 1999.

 C) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

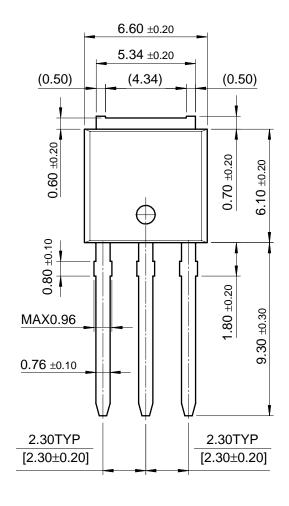
 - HEAT SINK TOP EDGE COULD BE IN CHAMFERED CORNERS OR EDGE PROTRUSION.

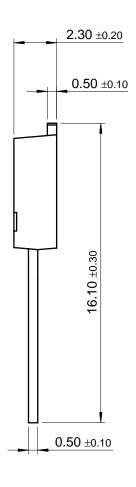
 DIMENSIONS L3,D,E1&D1 TABLE:

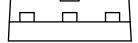
	OPTION AA	OPTION AB
L3	0.89-1.27	1.52-2.03
D	5.97-6.22	5.33-5.59
E1	4.32 MIN	3.81 MIN
D1	5.21 MIN	4.57 MIN



I-PAK







Dimensions in Millimeters





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